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Fellow of the Electrochemical Society

Fellow of IEEE

Education

Ph.D., Electrical Engineering, University of Waterloo, Waterloo, Canada, 1988
M.S., Management, New Jersey Institute of Technology, 1997
M.A.Sc., Electrical Engineering, University of Waterloo, Waterloo, Canada, 1985
M.Tech., Solid-State, IIT Delhi, India, 1983
M.S., Physics, Utkal University, Bhubaneswar, India, 1981
B.S., Physics, Utkal University, Bhubaneswar, India, 1978

Academic Experience

New Jersey Institute of Technology,
Newark, NJ

2011- Associate Chair for Graduate Studies, ECE Dept
2006 – 2008 Associate Chair for Graduate Studies, ECE Dept
2002 - Professor, Electrical & Computer Eng. Dept.
2002 – Director, Graduate Program: MS Electrical Eng
1993 - 2002 Associate Professor, Elect & Comp Eng Dept
1996 - 1997 Director, Microelectronics Research Center,
1988 - 1993 Assistant Professor, Elect & Comp Eng Dept
2017 Prof. Ramakrishna Rao Visiting Endowed Chair Professor at
Center for Nano Science and Engineering (CeNSE)
3/2016-5/2016 Visiting Professor, Inst. for Applied Research
1/2016-3/2016 Visiting Professor, Center for Nano Sc. & Eng.
1/2009-5/2009 Visiting Professor, Electrical Engineering Dept
1991 & 1992 Visiting Research Professor, Electrical Eng
1985 – 1988 Research Assistant
1984 – 1988 Teaching Assistant

Indian Institute of Science, Bangalore, India

Furtwangen University, Furtwngen, Germany
Indian Institute of Science, Bangalore, India
IIT Bombay, Mumbai, India
University of Waterloo, Canada

Industrial Experience

Bell Labs, Lucent Technologies, NJ
Sarnoff Corporation, Princeton, NJ

1997 - 1998 Visiting Professor in VLSI Research Dept
1990 – 1990 Visiting Professor at SEMATECH Center of Excellence in
Plasma Processing
1983 – 1983 Research Engineer

Cement Research Corporation, New Delhi, India

Consulting Experience

Keystone Venture Capital 2000-2001 High Speed CMOS Circuits
Lucent Technologies 1996-1998, Plasma Process Induced Damage, Murray Hill, NJ
Infinite Computer Technologies 1996-1998, Non-volatile Random-Access Memory, Alexandria
Rubicon, Inc., 1997-1998, Development of Circuits for Ferroelectric Memory, Princeton, NJ Memory
Semiconductor Assembly Council, 1996-1997, Development of a Standard Qualifying Die Mountain View, CA

Honors and Awards

- Fellow of the Institute of Electrical and Electronics Engineers (IEEE)
- IEEE Electron Device Society Board of Governors Member (Elected) (2014-2020)
- Chair, IEEE EDS Device Reliability Physics Committee (2016-2017)
- Thomas D. Callinan Award of the Dielectric Science and Tech Division of The Electrochemical Society, 2013
- Electronics and Photonics Division Award of The Electrochemical Society, 2013

- Fellow of the Electrochemical Society (ECS), Class of 2006
- Board Member, The Electrochemical Society Board of Governors 2008 – 2010
- Chair, Dielectric Science and Technology Division of ECS 2008 – 2010
- Excellence in Teaching Award, New Jersey Institute of Technology, 2005
- Southern Area Chair, IEEE Region 1 2008 - 2011
- 2008 Leadership Award, IEEE Princeton, Central Jersey Section (Conference Chair, Sarnoff Symposium)
- Chair, IEEE Electron Device Society SRC, North America East (Regions 1, 2, 3 and 7) 2006 - Present
- IEEE Electron Device Society Distinguish Lecturer, 2005 - Present
- IEEE Member and Geographic Activities Board Leadership Award (International) November 2004.
- IEEE North Jersey Section Service Award as Chair, December 1, 2004.
- Editorial Board, Materials (a MDPI journal), since 2015
- Guest Editor, Wide Bandgap Materials and Devices, Microelectronics Reliability, 2018
- Guest Editor, Interface, Vol. 26(4), 2017.
- Associate Editor, IEEE Circuits and Devices Magazine, 2001-2006(end).
- Editorial Board, Interface, Electrochemical Society, 2007-Present
- IEEE Region 1 Award for Distinguish Service for NJ Section and Service to ED Society, 2002.
- Awards Committee Chair, Thomas D. Callinan Award, Electrochemical Society, May 2000-02.
- IEEE North Jersey Section Award for “Distinguish Service and Leadership, 2003.
- Symposium Chair, Dielectric Science & Technology Division, ECS, May 2002-2004.
- Secretary, Dielectric Science & Technology Division, Electrochemical Soc., May 2004-2006.
- Program Chair, International Conference on Information Technology, India, Dec. 21-23, 2000.
- National Science Foundation Panel Review Member, June 1998, May 2001 and Oct. 2003.
- Board Member, National Institute of Science & Technology, India.
- Certificate of Achievement by McNair Achievement Program, NJIT, April 14, 2000.
- Certificate of Achievement by University Research Experience Program, NJIT, April 17, 1998.
- Recognition award by The Minority Academic Carriers Program, State of New Jersey, 1997.
- Recognition award by The Minority Academic Carriers Program, State of New Jersey, 1996.
- Canadian Commonwealth Scholarship Sept. 1983-July, 1988 at University of Waterloo.
- Dean of Graduate Studies Scholarship Sept.85 & May86 at Univ. of Waterloo.

Awards Received by My Students

1. PhD Student Wei Zhong received ECE Department **Hashimoto Award for Best Dissertation** in 2001, \$2,500.
2. Undergraduate Student Nasif Akand received ECE Department **Best Senior Project Award**, May 3, 2001, \$250.
3. Undergraduate Student Rafal Korczeniewski received **Honorable Mention** for Senior Project, First Industry-University Senior Project with Lucent Technologies, May 3, 2001.
4. **Best Poster Paper Award** in Ninth Annual UNI-Tech Conference, Newark, NJ, April 2000.
5. Tias Kundu, **IEEE North Jersey Section Best Graduate Student Research Presentation** for her presentation on “Deuterium Passivation At The Interface of Si And SiO₂- Reliability Of Thin Oxides,” IEEE North Jersey Student Presentation Contest held at Fairleigh Dickinson University in March 2003.
7. Purushothamn Srinivas, **IEEE North Jersey Section Honorable Mention Graduate Student Research Presentation** for his presentation “Study on Degradation of N-MOSFETs due To Hot Electron Effect,” IEEE North Jersey Student Presentation Contest held at Fairleigh Dickinson University in March 2003.
9. Reenu Garg, **The Electrochemical Society Student Travel Award and GSA Travel Award** to present her paper “Properties of Thermally Evaporated HfO₂,” at 203rd Meeting of the Electrochemical Society, (Abstract #54), Paris, France April 27-May 2, 2003.
10. Ami Patel, **Electrical and Computer Engineering Department Senior Design Project Poster Presentation Workshop - 2nd BEST POSTER PRESENTATION** for her Poster “Passivation of Silicon Nanocrystals through Computer Simulation” May 2003.
11. Purushothaman Srinivasan, **2003 International Semiconductor Device Research Symposium Student Award**

- (Registration Waiver) to present his paper “Screening of Si-H bonds during plasma processing,” at 2003 International Semiconductor Device Research Symposium (ISDRS), December 10-12, Washington, DC, 2003.
12. Purushothaman Srinivasan, ***The Inter University Microelectronics Center (IMEC), Belgium Student Travel Award and a Scholarship*** to work on a Research Project “Noise in High-K Dielectrics for sub 45nm CMOS Devices,” October 1, 2004 to January 31, 2005.
 13. Naser Chowdhury, ***The Electrochemical Society Student Travel Award*** to present his paper “Time Dependent Dielectric Breakdown of Thermally Evaporated HfO₂ for Nanoscale Devices,” at 206th Meeting of the Electrochemical Society, Honolulu, HI, October 3-8, 2004.
 14. Naser Chowdhury, ***GSA Achievement Travel Award*** to present his paper “Charge Trapping Characteristics of TiN/HfSi_xO_y/SiO₂/p-Si MOS Devices under Stress,” at the International Workshop on Electrical Characterization and Reliability for High-K Devices, Austin, TX, November 4-5, 2004.
 15. Waqas Mahmood, ***Gold Award Winner, Fall 2004, Senior Design Project Presentation***, for his project “Charge Trapping and Time Dependent Dielectric Breakdown (TDDB) of HfSi_xO_y Gate Stack under Constant Current and Voltage Stress.” December 9, 2004.
 16. Tias Kundu, ***IEEE North Jersey Section 1st Prize for Graduate Student Research Presentation*** for her paper presentation on “Hydrogen / Deuterium Implantation For Si/SiO₂ Interface Passivation,” IEEE North Jersey Student Presentation Contest held at FDU on March 22, 2005.
 19. Purushothaman Srinivasan, ***IEEE North Jersey Section 2nd Prize for Graduate Student Research Presentation*** for his paper presentation on “Modeling And Simulation of SiGe Photodiode for Optical Communication Applications,” IEEE North Jersey Student Presentation Contest held at FDU on March 22, 2005.
 21. Waqas Mahmood, ***Saul K. Fenster Innovation in Design Award*** for his project “Charge Trapping and Time Dependent Dielectric Breakdown (TDDB) of HfSi_xO_y Gate Stack under Constant Current and Voltage Stress.” April 8, 2005.
 22. Purushothaman Srinivasan, ***The Electrochemical Society Student Travel Award*** to present his paper “1/f Noise Performance of NMOSFETs with Hf-Based Gate Dielectrics,” at 207th Meeting of the Electrochemical Society, Quebec City, Canada, May 15-20 2005.
 23. Purushothaman Srinivasan and Naser Chowdhury ***First Prize in the PhD category at the Einstein Expo, a Student Research Conference at The City College of New York*** for "Study of electrically active traps in high-k dielectrics" The posters were evaluated by four Nobel laureates and eminent professors working in various research areas.
 24. Purushothaman Srinivasan, ***GSA Achievement Travel Award*** to present his paper “1/f Noise Performance of NMOSFETs with Hf-Based Gate Dielectrics,” at 207th Meeting of the Electrochemical Society, Quebec City, Canada, May 15-20 2005.
 25. Purushothaman Srinivasan, ***The Inter University Microelectronics Center (IMEC), Belgium Student Travel Award and a Scholarship*** to work on a Research Project “Noise in High-K Dielectrics for sub 45nm CMOS Devices,” June 1, 2005 to January 15, 2006.
 26. Tias Kundu ***The Electrochemical Society Student Travel Award*** to present her paper “Annealing Effect On Reliability Of SiO₂ For Deuterium Implanted Silicon Annealing,” at the 208th Meeting of the Electrochemical Society, Los Angeles, October 16-21, 2005.
 27. Naser Chowdhury, ***The Electrochemical Society Student Travel Award*** to present his paper “Evidence of Deep Energy States from Low Temperature Measurements and its Role in Charge Trapping in Metal Gate/Hf-Silicate Gate Stacks, at the 208th Meeting of the Electrochemical Society, Los Angeles, October 16-21, 2005.
 28. Reenu Garg, ***The Electrochemical Society Student Travel Award*** to present her paper “Effect of Nitridation on Ge/HfO₂ Interface, at the 208th Meeting of the Electrochemical Society, Los Angeles, October 16-21, 2005.
 29. P. Srinivasan, ***The Electrochemical Society Student Travel Award*** to present his paper “Effect of Nitridation on 1/f Noise in n-MOSFETs with High-k Dielectric, at the 208th Meeting of the Electrochemical Society, Los Angeles, October 16-21, 2005.
 30. Purushothaman Srinivasan, ***Winner of HASHIMOTO fellowship***, 2005-2006, ECE Department, Newark College Of Engineering, New Jersey Inst. of Technology.
 31. N. A. Chowdhury, ***ISDRS Travel Award and Registration Waiver*** to present his paper “Trapping in Deep Defects under Substrate Hot Electron Stress in TiN/Hf-silicate Based Gate Stacks”, at the International Semiconductor Device Research

- Symposium (ISDRS), Bethesda, Maryland, Dec., 2005.
32. N. A. Chowdhury, **2006 Summer Intern at SEMATECH**, Austin, TX to work on his research.
 33. P. Srinivasan, **2006 Summer Intern at IBM T.J. Watson Research Center** to work on his research.
 34. Purushothaman Srinivasan, **IEEE North Jersey Section 1st Prize for Graduate Student Research Presentation** for his paper presentation on “Low-frequency 1/f Noise Performance in MOSFET Devices,” IEEE North Jersey Student Presentation Contest held at NJIT on March 21, 2006.
 35. Nilufa Rahim, **The Electrochemical Society - Student Travel Award** to present her paper “Role of Bulk HfO₂ and Interfacial SiO₂ Layer in Breakdown Characteristics of TiN/HfO₂/SiO₂/Si Gate Stacks,” at the 210th Meeting of the Electrochemical Society, Washington, DC, October 7-12, 2007.
 36. Nilufa Rahim, **Best Research Award** in Newark College of Engineering on “GSA Research Day” for her poster “Breakdown characteristics of metal gate/HfO₂ based multi layer gate stacks,” November 14, 2007.
 37. Nilufa Rahim, **Selected to Present a Poster at the National Science Foundation (NSF)** headquarters on February 29 at the NSF GK-12 Annual Meeting. The NSF committee reviewed around 100 abstracts and chose 30 to be presented.
 38. Nilufa Rahim, **Graduate Students Association - Student Travel Award** to present her paper “NBTI Behavior of Ge/HfO₂/Al Gate Stacks,” at the IEEE International Reliability Physics Symposium, 2008.
 39. Nilufa Rahim, **The Bronze Award at the CIE-GNYC (Chinese Institute of Engineers- Greater NY Chapter) Annual Convention** at Marriot Hotel, Newark Liberty Airport for her paper “Breakdown studies of metal gate/high-k dielectric on Si substrate” November 8, 2008.
 40. Nilufa Rahim, **The Electrochemical Society - Student Travel Award** and **Graduate Student Association Travel Award** to present a paper on “Low Voltage SILC Analysis for High-k/Metal gate Dielectrics” at the 215th Meeting of the Electrochemical Society, San Francisco, CA, May 24- May 29, 2009.
 41. Nilufa Rahim, **The Best Poster Award at the Graduate Students Research Day, November 11, 2009** for the paper “Low Voltage SILC Analysis for High-k/Metal gate Dielectrics”

RESEARCH

Research Interests

Solid State Electronic Devices and Materials includes Nanoscale Semiconductor Devices; CMOS Device Gate Stack Reliability with High-K; Integrated sensors including photodetector and MEMS Microconcentrator; Very Large Scale Integration (VLSI) designs includes CMOS Circuits, Electronic Imaging circuits and various algorithms.

Research Collaboration with Industries and Academics

TEL Technology Center, America
 Globalfoundries, US Inc
 Indian Institute of Science, Bangalore, India
 IMEC, Belgium
 IIT Bombay, Mumbai, India
 SEMATECH, Austin, TX
 IBM TJ Watson Research Center, Yorktown Heights, NY
 Lucent Technologies, Murray Hill, NJ
 Infinite Computer Technologies, Alexandria, VA
 Rubicon, Inc., Princeton, NJ
 Sarnoff Corporation, Princeton, NJ
 Semiconductor Assembly Council, Mountain View, CA
 Amkor Electronics Inc., Chandler, AZ
 Radiation Monitoring Devices, Watertown, MA
 Alphasel, Mendham, NJ
 Affiliated Engineering Laboratories, Inc., Edison, NJ

Research Collaboration with Federal Laboratories

Naval Research Laboratories, Washington, DC
ARMY Research Laboratory, Ft Monmouth, NJ

Publication of Edited Books

1. D. Misra, Z. Chen, D.-K Ko, Y. Obeng, D. Bauza, T. Chikyow, (Editors), *Dielectrics for Nanosystems 8: Materials Science, Processing, Reliability, and Manufacturing*, **ECS Transactions**, Vol. 97(1), (ISBN 978-1-60768-889-1), Pennington, NJ, 159 pages, May 2020.
2. H. Jagannathan, K. Kakushima, P. J. Timans, E. Gusev, Z. Karim, S. De Gendt, D. Misra, Y. S. Obeng, F. Roozeboom,, (Editors), *Silicon Compatible Emerging Materials, Processes, and Technologies for Advanced CMOS and Post-CMOS Applications 10*, **ECS Transactions**, Vol. 97(3), 102 pages, 2020.
3. D. Misra, S. De Gendt, S. H. Kilgore, K. Kita, S. Dayeh, K. Kakushima (Editors), *Semiconductors, Dielectrics, and Metals for Nanoelectronics 17*, **ECS Transactions**, Vol. 92(1), 99 pages, 2019.
4. F. Roozeboom, P. J. Timans, K. Kakushima, E. Gusev, Z. Karim, D. Misra, Y. S. Obeng, S. De Gendt, H. Jagannathan (Editors), *Silicon Compatible Emerging Materials, Processes, and Technologies for Advanced CMOS and Post-CMOS Applications 9*, **ECS Transactions**, Vol. 89(3), 161 pages, 2019.
5. D. Misra, S. De Gandt, S. Dayeh, K. Kita, (Editors), *Semiconductors, Dielectrics, and Metals for Nanoelectronics 16*, **ECS Transactions**, Vol. 86, No. 2, Pennington, NJ, 85 pages, October 2018.
6. D. Misra, S. De Gandt, M. Houssa, K. Kita, D. Landheer (Editors), *Semiconductors, Dielectrics, and Metals for Nanoelectronics 15 In Memory of Samares Kar*, **ECS Transactions**, Vol. 80, No. 1, Pennington, NJ, 395 pages, October 2017.
7. D. Misra, P. Hesketh, Z. Karim, S. De Gandt, Y. Obeng, P. Srinivasan (Editors), *Emerging Materials for Post CMOS Devices/Sensing and Applications 8*, **ECS Transactions**, Vol. 77, No. 2, Pennington, NJ, 109 pages, May 2017.
8. S. Kar, K. Kita, D. Landheer, D. Misra (Editors), *Semiconductors, Dielectrics, and Metals for Nanoelectronics 14*, **ECS Transactions**, Vol. 75, No. 5, (ISBN 978-1-62332-364-6), Pennington, NJ, 319 pages, October 2016.
9. D. Misra, D. Bauza, Z. Chen, K.B. Sandaram, Y. Obeng, T. Chikyow, H. Iwai, (Editors), *Dielectrics for Nanosystems 7: Materials Science, Processing, Reliability, and Manufacturing*, **ECS Transactions**, Vol. 72, No. 2, (ISBN 978-1-62332-354-7), Pennington, NJ, 353 pages, May 2016.
10. S. Kar, K. Kita, D. Landheer, D. Misra (Editors), *Semiconductors, Dielectrics, and Metals for Nanoelectronics 13*, **ECS Transactions**, Vol. 69, No. 5, (ISBN 978-1-62332-312-7). Pennington, NJ, 374 pages, October 2015.
11. S. Kar, M. Houssa, S. Van Elshocht, D. Misra, K. Kita, D. Landheer, S. A. Dayeh, H. Jagannathan (Editors), *Semiconductors, Dielectrics, and Metals for Nanoelectronics 12*, **ECS Transactions**, Vol. 66 No. 8, (ISBN 978-1-62332-188-8) Pennington, NJ 191 pages, October 2014.
12. **D. Misra**, D. Bauza, Z. Chen, Y. Obeng, T. Chikyow, H. Iwai (Editors), *Dielectrics for Nanosystems 6: Materials Science, Processing, Reliability, and Manufacturing* **ECS Transactions**, Vol. 61 No. 2, (ISBN: 978-1-62332-161-1) Pennington, NJ 410 pages, May 2014.
13. S. Kar, M. Houssa, S. Van Elshocht, **D. Misra**, K. Kita, D. Landheer, H. Jagannathan (Editors), *Semiconductors, Dielectric, and Metals for Nanoelectronics 11*, **ECS Transactions**, Vol. 58 No. 7, (ISBN: 978-1-62332-098-0) Pennington, NJ 391 pages, October 2013.
14. **D. Misra**, S. DeGendt, Y. S. Obeng, P. Srinivasan, Z. Karim (Editors), *Graphene, Ge/III-V, and Emerging Materials for Post CMOS Applications 5*, **ECS Transactions**, Vol. 53 No. 1, (ISBN: 978-1-62332-023-2) Pennington, NJ 371 pages, May 2013.
15. M. J. Deen, **D. Misra**, D. N. Buckley (Editors), *Integrated Optoelectronics 6*, **ECS Transactions**, Vol. 45 No. 33, (ISBN: 978-1-62332-056-0 PDF) Pennington, NJ 67 pages, 2013.
16. S. Kar, S. Van Elshocht, K. Kita, D. Misra (Editors), *Dielectric Materials and Metals for Nanoelectronics and Photonics 10*, **ECS Transactions**, Vol. 50 No. 4, (ISBN: 978-1-62332-003-4) Pennington, NJ 358 pages, October 2012.
17. **D. Misra**, D. Bauza, Z. Chen, T. Chikyow, H. Iwai, Y. Obeng, S. Datta (Editors), *Dielectrics for Nanosystems 5: Materials Science, Processing, Reliability, and Manufacturing -and- Tutorials in Nanotechnology: More than Moore - Beyond CMOS Emerging Materials and Devices*, **ECS Transactions**, Vol. 45 No. 3, (ISBN: 978-1-56677-955-5) Pennington, NJ 598 pages, May 2012.
18. Y. Obeng, S. De-Gendt, Z. Karim, **D. Misra**, P. Srinivasan (Editors), *Graphene, Ge/III-V, Nanowires, and Emerging Materials for Post-CMOS Applications 4*, **ECS Transactions** (Volume 45, no. 4, 242 pages, ISBN 978-1-56677-956-2, Hardcover-May 2012).

19. S. Kar, M. Houssa, S. Van Elshocht, **D. Misra**, K. Kita (Editors), *Physics and Technology of High-k Materials 9*, **ECS Transactions**, Vol. 41 No. 3, (ISBN: 978-1-56677-903-6) Pennington, NJ 492 pages, October 2011.
20. K. Sundaram, **D. Misra**, H. Iwai, J. Fenton (Editors), *ECS Transactions*, Volume 41, no. 34, 50 pages, ISBN 978-1-56677-974-6, PDF-2012 "Solid State Topics (General)."
21. K. Kondo, F. Roozeboom, R. Akolkar, M. Koyanagi, **D. Misra** (Editors), *Processing Materials of 3D Interconnects, Damascene and Electronics Packaging*, *ECS Transactions*, Volume 41, no. 43, 134 pages, ISBN 978-1-56677-985-2, PDF-2012.
22. Z. Karim, **D. Misra**, P. Srinivasan, Y. Obeng, S. De Gendt, (Editors), **ECS Transactions** (Volume 35, no. 3, 532 pages, ISBN 978-1-56677-884-0, Hardcover-May 2011), "Dielectrics in Nanosystems and Graphene, Ge/III-V, Nanowires and Emerging Materials for Post-CMOS Applications-3"
23. K. Sundaram, **D. Misra**, A. Baca (Editors), *ECS Transactions*, Volume 33, no. 31, 121 pages, ISBN 978-1-56677-889-3, PDF-October 2010) "Solid State Topics (General)."
24. S. Kar, M. Houssa, S. Van Elshocht, D. Landheer, **D. Misra**, K. Kita (Editors), *Physics and Technology of High-k Materials 8*, **ECS Transactions**, Vol. 33 No. 3, (ISBN: 978-1-56677-822-0) Pennington, NJ 605 pages, October 2010.
25. **D. Misra**, D. Bauza, Z. Chen, T. Chikyow, H. Iwai, and Y. Obeng (Editors), *Dielectrics for Nanosystems 4: Materials Science, Processing, Reliability, and Manufacturing*, **ECS Transactions**, Vol. 28 No. 2, (ISBN: 978-1-56677-792-6) Pennington, NJ 574 pages, April 2010.
26. P. Srinivasan, Z. Karim, Y. Obeng, S. De-Gendt, **D. Misra** (Editors), *Graphene, Ge/III-V, and Emerging Materials for Post-CMOS Applications 2*, **ECS Transactions**, Vol. 28 No. 5, (ISBN: 978-1-56677-795-7) Pennington, NJ 247 pages, April 2010.
27. Y. Obeng, S. De-Gendt, P. Srinivasan, **D. Misra**, H. Iwai, Z. Karim, D. Hess, H. Grebel (Editors), *Graphene and Emerging Materials for Post-CMOS Applications*, **ECS Transactions**, Vol. 19 No. 5, (ISBN: 978-1-56677-713-1) Pennington, NJ 407 pages, May 2009.
28. K. Worhoff, P. Mascher, **D. Misra**, K. Shiraishi (Editors), *Science and Technology of Dielectrics for Active and Passive Devices*, **ECS Transactions**, Vol. 16, No. 21, Pennington, NJ, (Online volume, Item No. ECSTF8000016000021), October 2008
29. S. Kar, D. Landheer, M. Houssa, D. Misra, S. Van Elshocht, H. Iwai (Editors), *Physics and Technology of High-k Gate Dielectrics 6*, **ECS Transactions**, Vol. 16, No. 5, Pennington, NJ, (ISBN 978-1-56677-651-6), 530 pages, October 2008.
30. **D. Misra**, H. Iwai, Y. Obeng, T. Chikyow, J. Vanhellemont (Editors), *Dielectrics for Nanosystems 3: Materials Science, Processing, Reliability, and Manufacturing*, **ECS Transactions**, Vol. 13 No. 2, (ISBN: 978-1-56677-627-1) Pennington, NJ 405 pages, May 2008.
31. S. Kar, S. De Gendt, M. Houssa, D. Landheer, **D. Misra**, and H. Iwai (Editors), *Physics and Technology of High-k Gate Dielectrics 5*, **ECS Transactions**, Vol. 11, No. 4, Pennington, NJ, (ISBN 978-1-56677-570-0), 552 pages, October 2007.
32. S. Kar, S. De Gendt, M. Houssa, D. Landheer, H. Iwai, and D. Misra (Editors) *Physics and Technology of High-k Gate Dielectrics 4*, **ECS Transactions**, Vol. 3, No. 3, Pennington, NJ, October 2006.
33. P. Mascher, K. Wörhoff, and D. Misra, (Editors), *Science and Technology of Dielectrics for Active and Passive Photonic Devices*, **ECS Transactions**, Vol. 3, No. 11, (Online) Pennington, NJ, October 2006.
34. H. Z. Massoud, J. H. Stathis, T. Hattori, D. Misra, and I. Baumvol (Editors), *Physics and Chemistry of SiO₂ and Si-SiO₂ Interface-5* **ECS Transactions** Vol. 1 No. 1, October 2005, Pennington, NJ (ISBN 1-56677-431-4).
35. S. Kar, D. Misra, H. Iwai, M. Houssa, D. Landheer, W. Tsai, S. De Gendt, and A. Chin (Editors), *High Dielectric Constant Gate Stacks III*, **ECS Transactions**, Vol. 1, No. 5 Pennington, NJ, March 2006.
36. D. Misra and H. Iwai, *Dielectrics for Nanosystems – II: Materials Science, Processing, Reliability, and Manufacturing*, **ECS Transactions** Vol. 2 No. 1, May 2006, Pennington, NJ (ISBN 1-56677-438-1).
37. L. Cook, D. Misra, S. Mukhopadhyay, W. Wong, O. Leonte, and K. Sundaram (Editors), *Interfaces in Electronic Materials*, *Electrochemical Society Proceedings* Volume, PV-2003-31, 334 pages, 2006 (ISBN 1-56677-425-X).
38. J.L. Davidson, P.J. Hesketh, **D. Misra**, and S. Shoji, (Editors), *Microfabricated Ststems and MEMS-VII*, *Electrochemical Society Proceedings* Volume PV-2004-09, 340 pages, 2004 (ISBN 1-56677-272-5).
39. S. Kar, R. Singh, **D. Misra**, H. Iwai, M. Houssa, J. Morais, and D. Landheer, *Physics and Technology of High-k Gate Dielectrics II*, *Electrochemical Society Proceedings* Volume PV-2003-22, (ISBN 1-56677-405-5), 490 pages, October 2003.
40. S. Kar, **D. Misra**, R. Singh, F. Gonzalez, *Physics and Technology of High-k Gate Dielectrics I*, *Electrochemical Society Proceedings* Volume PV-2002-28, (ISBN 1-56677-395-4), 304 pages, 2003.
41. **D. Misra**, K. Worhoff, and P. Mascher, *Dielectrics in Emerging Technologies*, *Electrochemical Society Proceedings* Volume PV-2003-1, (ISBN 1-56677-346-6), 436 pages, April 2003.
42. R. E. Sah, K. B. Sundaram, M. J. Deen, D. Landeer, W. D. Brown, and **D. Misra**, *Silicon Nitride and Silicon Dioxide Thin Insulating Films (7th)*, *Electrochemical Society Proceedings* Volume PV-2003-2, (ISBN 1-56677-347-4), 636

pages, April 2003.

43. M.J. Deen, **D. Misra** and J. Ruzyllo (Editors), Integrated Optoelectronics, Electrochemical Society Proceedings Volume PV-2002-4, 444 pages, 2002 (ISBN 1-56677-370-5).
44. P.J. Hesketh, S.S. Ang, J.L. Davidson, H.G. Hughes, and **D. Misra**, (Editors), *Microfabricated Systems and MEMS-VI*, Electrochemical Society Proceedings Volume PV-2002-6, 260 pages, 2002 (ISBN 1-56677-272-5).
45. K.B. Sundaram, M.J. Deen, D. Landheer, W.D. Brown, **D. Misra**, M.D. Allendorf and R.E. Sah, (Editors), *Silicon Nitride and Silicon Dioxide Thin Insulating Films - VI*, Electrochemical Society Proceedings Volume PV-2001-7, 286 pages, 2001 (ISBN 1-56677-3136-X).
46. R.K. Ghosh, and **D. Misra** (Editors), CIT 2000, Proceedings of the Third International Conference on Information, Tata McGraw-Hill Publishing, New Delhi, 308 pages, 2001. (ISBN 0-07-043546-4).
47. P.J. Hesketh, S.S. Ang, W.E. Bailey, J.L. Davidson, H.G. Hughes, **D. Misra**, (Editors), *Microfabricated Systems and MEMS-V*, Electrochemical Society Proceedings Volume PV-2000-19, 394 pages, 2000 (ISBN 1-56677-286-9).
48. K.B. Sundaram, M.J. Deen, W.D. Brown, R.E. Sah, E. Poindexter, **D. Misra**, M.D. Allendorf, and S.I. Raider, (Editors), *Silicon Nitride and Silicon Oxide Insulating Film - V*, Electrochemical Society Proceedings Volume PV-99-6, 284 pages, 1999. (ISBN 1-56677-228-1)
49. G.S. Mathad, D.W. Hess, Y. Horiike, T. Li, **D. Misra**, and L. Simpson, (Editors), *Plasma Etching Processes For Sub-Quarter Micron Devices*, Electrochemical Society Proceedings Volume PV-99-30, 378 pages, 1999. (ISBN 1-56677-253-2)
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101. P.K. Swain, D. Misra, Y. Qui, and P.E. Thompson, Effect of Dry Etching and Subsequent Annealing of Si/SiGe/Si Heterostructure, **Electrochemical Society Interface**, Vol. 4, No. 3, pp. 180, 1995.
102. D. Misra, A Book Review: "VLSI Fabrication Principle: Silicon and Gallium Arsenide" 2nd Ed., by Sorab K. Ghandi, John Wiley Interscience, 1994," **Semiconductor Science and Technology**, Vol. 10, pp. 213-214, February 1995.
103. V. Patel, W. Zhong, D. Misra, J. Gaudani, B. Bartynski, and B. Singh, Etch Induced Damage in High Density Inductively Coupled Plasma Etching Reactor, **Electrochemical Society Interface**, Vol. 3, No. 1, pp. 130, 1994.
104. W. Zhong, D. Misra, H. Amin, J. Gaudani, and M. Patel, Electrical studies on SF₆ and O₂ plasma etched Si_{1-x}Gex/Si p+ _n heterojunction, **Electrochemical Society Interface**, Vol. 2, No. 3, pp. 122, 1993.
105. O.W. Purbo, D. Misra and C.R. Selvakumar, "Reactive Ion Etching of SOI (ZMR and SIMOX) Silicon in CF₄ + O₂ and SF₆ + O₂ Plasmas," **Journal of Electrochemical Society**, Vol. 139, No. 3, pp. 151C, 1992.
106. D. Misra and E.L. Heasell, "Annealing Behavior of Reactive Ion Etching Induced Deep Levels," **Journal of Electrochemical Society**, Vol. 136, No. 3, pp. 121C, March 1989.

Invited Talks in National and International Conferences and Meetings

1. D. Misra, Invited IEEE EDS Distinguished Lecturer, "Challenges and Directions for Nanoelectronics to Nanotechnology," IEEE EDS NIT Silchar Student Chapter, Silchar, India, Online via WebEx. July 31, 2020.
2. D. Misra, Invited IEEE EDS Distinguished Lecturer, "Nanoelectronics to Nanotechnology: Challenges and Directions," IEEE EDS North Jersey Chapter, Online via Zoom. May 27, 2020.
3. D. Misra, Invited Talk, "Self-Heating in FinFETs and Its Impact on Logic Circuits," IEEE Latin American Electron Device Conference, San Jose, Costa Rica, February 27, 2020.
4. D. Misra, Invited IEEE EDS Distinguished Lecturer, "Nanoelectronics to Nanotechnology: Challenges and Directions," IEEE EDS Mini-Colloquium (MQ), San Jose, Costa Rica, February 25, 2020.
5. D. Misra, Invited IEEE EDS Distinguished Lecturer, "Nanoelectronics to Nanotechnology: Challenges and Directions," IEEE EDS Student Chapter, Heritage Institute of Technology, Kolkata, India, January 14, 2020.
6. D. Misra, Invited IEEE EDS Distinguished Lecturer, "Nanoelectronics to Nanotechnology: Challenges and Directions," IEEE EDS Student Chapter, National Institute of Science and Technology, Pallur Hills, India, January 9, 2020.
7. D. Misra, Invited IEEE EDS Distinguished Lecturer, "Nanoelectronics to Nanotechnology: Challenges and Directions," IEEE EDS Student Chapter, University Visvesvaraya College of Engineering, Bangalore, India, January 3, 2020.
8. D. Misra, Invited Talk, "Recent Advances in nanoelectronics and NJIT-SOA Collaboration," SOA University, Bhubaneswar, India, December 27, 2019.
9. D. Misra, Invited IEEE EDS Distinguished Lecturer, "Self-Heating in FinFETs: Characterization, Reliability and Impact on Logic Circuits," IEEE EDS Mini-Colloquium (MQ), Spain Chapter, Tarragona, Spain, Universitat Rovira i Virgili, Tarragona, Spain, May 24, 2019.
10. D. Misra, Keynote Presentation, XIV Workshop on Semiconductors and Micro and Nano Technology: SEMINATEC 2019, "Self-Heating in FinFETs and Its Impact on Logic Circuits," University of Campinas (UNICAMP), Campinas Brazil, April 11, 2019.
11. D. Misra, Invited IEEE EDS Distinguished Lecturer, "Future of Electronics: Nanoelectronics to Nanotechnology," IEEE EDS FEI University Student Chapter, FEI University, Sao Bernardo do Campo – Brazil, April 10, 2019.
12. D. Misra, Invited IEEE EDS Distinguished Lecturer, "Self-Heating in FinFETs and the Reliability Implications," IEEE EDS Colombia Chapter, Pontificia Universidad Javeriana, Bogota, Colombia, February 22, 2019.
13. D. Misra, Invited Presentation at Industry, Tokyo Electronics, "Role of High-k in Next Generation Devices: Germanium Gate Stacks to ReRAM Devices," TEL Technology Center America, Albany, New York, Albany Nanotech Center, 255 Fuller Rd, Ste 214, Albany, NY 12203, USA, January 23, 2019.
14. D. Misra, Invited IEEE EDS Distinguished Lecturer, "Next Generation Nanoelectronic Devices: Issues and Challenges," IEEE EDS Netaji Subhash Engineering College Student Branch Chapter, Netaji Subhash Engineering College, Kolkata, India, January 12, 2019.
15. D. Misra, Invited IEEE EDS Distinguished Lecturer, "How Reliable the Next Generation Nanoelectronic Devices: FinFETs to Ge Devices," IEEE EDS Lehigh Valley Chapter, Lehigh University, November 5, 2018.
16. D. Misra, IEEE XIII Workshop on Semiconductors and Micro & Nano Technology 2018, "How Reliable the Next Generation Nanoelectronic Devices: FinFETs to Ge Devices," IEEE, São Bernardo do Campo, Brazil, April 19, 2018.
17. D. Misra, Invited IEEE EDS Distinguished Lecturer, "How Reliable the Next Generation Nanoelectronic Devices: FinFETs to Ge Devices," IEEE EDS South Brazil Chapter, University of San Paulo, Brazil, April 18, 2018.
18. D. Misra, Invited Talk, "Why Do We do Characterization," CeNSE Lecture, Indian Institute of Science, Bangalore, January 8, 2018.
19. D. Misra, Invited Talk, "Trends in Gate Dielectric Scaling, Processing and Reliability Issues," Lam Research India, Bangalore, India, January 4, 2018.
20. D. Misra, Invited IEEE EDS Distinguished Lecturer, "Reliability Implications of Next Generation Nanoelectronic Devices" IEEE EDS Delhi Chapter, Indian Institute of Technology, Delhi, New Delhi, India, December 20, 2017.
21. D. Misra, Keynote Talk, "Challenges of Converging Nanoelectronics and Nanotechnology for Internet of Things," IEEE International Symposium on Nanoelectronic and Information Systems (IEEE-iNIS), Bhopal, India, December 18, 2017.
22. D. Misra, Invited IEEE EDS Distinguished Lecturer, "Challenges for Nanoelectronics: More Moore and More than Moore," IEEE EDS Ottawa Chapter ay 5th International Workshop on High-Performance Chip, Packaging and Systems, Carleton University, Ottawa, Canada, September 23, 2017.
23. D. Misra, Invited Talk, "Low Power Requirement in Nanoscale CMOS Devices and Introduction of High-k Materials," Indian Institute of Science, Bangalore, India, Indian Institute of Science, Bangalore, India, August 28, 2017.
24. D. Misra, Invited Talk, "Dielectric-Semiconductor Interface with High-k Gate Dielectrics," Indian Institute of Technology Madras, Chennai, India, Indian Institute of Technology Madras, Chennai, India, August 16, 2017.

26. D. Misra, Invited IEEE EDS Distinguished Lecturer, "Interface Issues in Ge/High-k Gate Stacks: Can it be solved?" IEEE EDS Chengdu Chapter, University of Electronic Science and Technology, China, July 20, 2017.
27. D. Misra, Invited IEEE EDS Distinguished Lecturer, "High-k Gate Stacks Processing and Reliability on Si and Ge Substrates," IEEE EDS Nanjing Chapter, School of Electronic Science & Engineering, Southeast University, Nanjing, China, July 18, 2017.
28. D. Misra, Invited Talk, "Solving the Interface Problem in Ge/High-k Gate Stack," International Semiconductor Conference for Global Challenges (ISCGC 2017), Nanjing, China, July 17, 2017.
29. D. Misra, Invited Talk, "Next Generation NanoSystems: Scientific and Technical Challenges," Ramakrishna Mission, Kolkata, India, Ramakrishna Mission, Kolkata, India, January 10, 2017.
30. D. Misra, Invited Talk, "Challenges in nanoelectronics, Nanotechnology and Information Technology for Internet of Things (IoT)," Assam University, Silchar, Assam, India, January 9, 2017.
31. D. Misra, 5-Day Short Course; GIAN Lecture Series "Nanoelectronics Challenges for Internet of Things," GIAN: Global Initiative of Academic Networks, Ministry of Human Resource Development, Govt. of India, National Institute of Technology, Silchar, Assam, India, January 5-9, 2017.
32. D. Misra, Reduction of Interface States in Ge/High-K Gate Stacks and its Reliability Implications, 13th IEEE ICSICT, Hangzhou, China, October 27, 2016.
33. D. Misra, Scientific and Technical Challenges for Building NanoSystems, Zhejiang Sci-Tech University, Hangzhou, China, October 25, 2016.
34. D. Misra, "High-k Gate Stacks Processing on Si and Ge Substrates for sub-14nm CMOS Technology, IEEE EDS Mini-Colloquium, Hangzhou Dianzi University, Hangzhou, China, October 24, 2016.
35. D. Misra, "Visiting United States in General and at NJIT in Particular for Exchange Student or Graduate Studies," International Center of Furtwangen University (HFU), Furtwangen University's Schwenningen Campus. May 11, 2016.
36. D. Misra, "Introduction to CMOS VLSI Design," Microsystems Department, Furtwangen University, Furtwangen University's Furtwangen Campus, Germany. May 10, 2016.
37. D. Misra, Invited IEEE EDS Distinguished Lecturer, "Processing and Reliability of Higher-k Gate Stacks for sub-14nm CMOS Technology," IEEE EDS Germany Chapter, IMS-Chips, The Institute for Microelectronics, Stuttgart, Germany. May 3, 2016.
38. D. Misra, Invited Talk, "Dielectric-Semiconductor Interface with Higher-k Gate Dielectrics for sub-14nm CMOS Technology," The Institute of Applied Physics (IAP), Technical University of Freiberg, Germany. April 29, 2016.
39. D. Misra, Invited Talk, "Higher-k Gate Dielectrics for sub-14nm CMOS Technology: Processing and Reliability," NamLab, Technical University of Dresden, Germany, Technical University of Dresden, Germany. April 28, 2016.
40. D. Misra, Invited Guest Lecture, "More Moore or More than Moore: CMOS High-k Gate Stacks to Nanotechnology," Microsystems Department, Furtwangen University, Furtwangen University's Furtwangen Campus, Germany. April 26, 2016.
41. D. Misra, Invited Tutorial, "CMOS Processing Technology," Microsystems Department, Furtwangen University, Furtwangen University's Furtwangen Campus, Germany. April 26, 2016.
42. D. Misra, Invited Talk, "How to be Innovative in a Start-up: The US Perspective," Business School of Furtwangen University (HFU), Furtwangen University's Schwenningen Campus, Germany. April 22, 2016.
43. D. Misra, Invited Talk, "How to move forward as a Researcher and Innovate," Department of Medical Engineering of Furtwangen University (HFU), Furtwangen University's Schwenningen Campus, Germany. April 21, 2016.
44. D. Misra, Invited Guest Lecture, "Interface State Density and Role of Hydrogen in Dielectrics and Interfaces," Microsystems Department, Furtwangen University, Furtwangen University's Furtwangen Campus, Germany. April 19, 2016.
45. D. Misra, Invited Talk, "Exchange Students at NJIT and in the USA," International Center of Furtwangen University (HFU), Furtwangen University's Tuttlingen Campus, Germany. April 13, 2016.
46. D. Misra, Invited IEEE EDS Distinguished Lecturer, "More Moore or More than Moore: CMOS High-k Gate Stacks to Nanotechnology," IEEE EDS SJCE Student Chapter, Sri Jayachamarajendra College of Engineering, Mysore, India. March 8, 2016.
47. D. Misra, Invited IEEE EDS Distinguished Lecturer, "Dielectric-Semiconductor Interface with High-k Gate Dielectrics," IEEE EDS Bombay Chapter, Indian Institute of Technology Bombay, Mumbai, India. March 4, 2016.
48. D. Misra, Invited Talk at 10th Chandigarh Science Congress: CHASCON 2016, "Scientific and Technical Challenges for Nanometer-scale CMOS Technology," Punjab University, Chandigarh, Punjab University, Chandigarh, India. February 29, 2016.
49. D. Misra, Invited IEEE EDS Distinguished Lecturer, "Higher-k Gate Stacks for sub-14nm CMOS Technology," IEEE EDS Bangalore Chapter, Indian Institute of Science, Bangalore, India. February 24, 2016.

50. D. Misra, Invited IEEE EDS Distinguished Lecturer, "More Moore or More than Moore: CMOS High-k Gate Stacks to Nanotechnology," IEEE EDS Calcutta Chapter, Silicon Institute of Technology, Bhubaneswar, India. February 22, 2016.
51. D. Misra, Invited IEEE EDS Distinguished Lecturer, "High-k Gate Dielectrics and Dielectric-Semiconductor Interface for sub-14nm CMOS Technology," IEEE EDS NIST Student Chapter, National Institute of Science and Technology, Berhampur, India. February 20, 2016.
52. D. Misra, Invited Research Presentation, "Breakdown of MOS devices with multilayer high-k gate stacks," Center for Nano Science and Engineering (CeNSE), Indian Institute of Science, Bangalore, India. February 17, 2016.
53. D. Misra, Invited Research Presentation, "Charge Trapping & Reliability in High-K Devices," Center for Nano Science and Engineering (CeNSE), Indian Institute of Science, Bangalore, India. February 16, 2016.
54. D. Misra, Invited Research Presentation, "Interface State Density and Role of Hydrogen in Dielectrics and Interfaces," Center for Nano Science and Engineering (CeNSE), Indian Institute of Science, Bangalore, India. February 15, 2016.
55. D. Misra, Invited Talk, "More Moore or More than Moore: CMOS High-k Gate Stacks to Nanotechnology," SHRI RAMDEOBABA COLLEGE OF ENGINEERING & MANAGEMENT, SHRI RAMDEOBABA COLLEGE OF ENGINEERING & MANAGEMENT. February 6, 2016.
56. D. Misra, Invited Talk, "More Moore or More than Moore: CMOS High-k Gate Stacks to Nanotechnology," VLSI and Nanotechnology Center, Visvesvaraya National Institute of Technology, Nagpur, India. (February 5, 2016).
57. D. Misra, Invited Talk, "Research and Development in the US: How to move forward as a Researcher/Faculty," Electronics and Communication Department, Visvesvaraya National Institute of Technology, Nagpur, India. February 5, 2016.
58. D. Misra, Invited Talk, "Research Internship: International Undergraduate Research Experience," Electronics and Communication Department, Visvesvaraya National Institute of Technology, Nagpur, India. February 5, 2016.
59. D. Misra, Thin films and Nanomaterials for Device Applications (TNDA-2016), "More than Moore: Creating a Perfect Dielectric-Semiconductor Interface with High-k Gate Dielectrics," NMIT, Bangalore, Nitte Meenakshi Institute of Technology (NMIT), Bangalore, India. January 22, 2016.
60. D. Misra, Invited IEEE EDS Distinguished Lecturer, "Creating a Perfect Dielectric-Semiconductor Interface with High-k Gate Dielectrics for sub-14nm CMOS Technology," IEEE EDS Delhi Chapter/Department of Electronics Science, Delhi University, New Delhi, India. January 13, 2016.
61. D. Misra, Invited IEEE EDS Distinguished Lecturer, "Creating a Perfect Dielectric-Semiconductor Interface with High-k Gate Dielectrics for sub-14nm CMOS Technology," IEEE EDS Calcutta Chapter/Institute of Radio Physics and Electronics, Calcutta University, Kolkata, India. January 11, 2016.
62. D. Misra, Invited Talk, "Creating a Perfect Dielectric-Semiconductor Interface with High-k Gate Dielectrics for sub-14nm CMOS Technology," Center for Nano Science and Engineering (CeNSE), Indian Institute of Science, Bangalore, India. January 7, 2016.
63. D. Misra, Dielectric-Semiconductor Interface for High-k Gate Dielectrics for sub-16nm CMOS Technology, EDSSC 2015, Singapore, June 2, 2015.
64. D. Misra, Integration of Nanoelectronics, Nanotechnology and Information Technology: Future Research Challenges, PES University, Bangalore, India, January 6, 2015.
65. D. Misra, High-k Gate Dielectrics for sub-16nm CMOS Technology, University of Electronic Science and Technology of China, Chengdu, China, July 21, 2014.
66. D. Misra, High-K Gate Stack and Reliability Requirements for Sub-16nm CMOS Technology, SEMINATEC 2014, IX Workshop on Semiconduction and Micro & Nano Technology, São Paulo, Brazil, April 25, 2014.
67. D. Misra, Invited Distinguished Lecturer, "Scaling and Reliability Challenges for sub-16nm CMOS Technology," Fudan University, Shanghai, China, March 14, 2014.
68. D. Misra, Invited Distinguished Lecturer, "Integration of Information Technology and Nanoelectronics: Direction and Challenges," Panipat Institute of Engineering Technology, Panipat, India, Panipat, Haryana, India, August 19, 2013.
69. D. Misra, Invited Distinguished Lecturer, "Convergence of Nanoelectronics, Nanotechnology and Information Technology: Future challenges," IEEE EDS Student Chapter, HIT Kolkata, Calcutta Section, Kolkata, India, August 14, 2013.
70. D. Misra, Invited Distinguished Lecturer, "Next Generation of Nanoelectronics: More Moore and/or More than Moore," IEEE EDS/SSC Chapter of Gujarat Section, Rajkot, Gujarat, India, August 7, 2013.
71. D. Misra, Invited Distinguished Lecturer, "Challenges for Nanoelectronics Innovation: More Moore and/or More than Moore," Larsen & Toubro Integrated Engineering Services, Bangalore, India, Bangalore, India, January 8, 2013.
72. D. Misra, 2013 International Conference on Emerging Trends in VLSI, Embedded System, Nano Electronics and Telecommunication System, "High-k on High-Mobility Substrate: In Interface Challenge," Tiruvannamalai, TN, India, January 7, 2013.

73. D. Misra, Invited Distinguished Lecturer, "“More Moore” or “More than Moore”: Challenges for Nanoelectronics," Thiagarajar College of Engineering, Madurai, TN, India, Madurai, TN, India, January 4, 2013.
74. Misra, D. (Presenter Only), Invited Distinguished Lecturer, "Technical Challenges for Nanoelectronics and Beyond," Xidian University, Xi'an, China, Xi'an, China, October 29, 2012.
75. D. Misra, Invited Distinguished Lecturer, "Challenges for Nanoelectronics and Beyond: More Moore and/or More than Moore," Tsinghua University, Beijing, China, Beijing, China, October 26, 2012.
76. D. Misra, "High-k Dielectrics and Nanotechnology" Samsung Advanced Institute of Technology, Seoul, South Korea, June 14, 2011
77. D. Misra, "High-K Dielectrics on High-Mobility Substrates," IEEE Mini-Colloquium, Concordia University, Montreal, Canada, April 29, 2011.
78. D. Misra, "A Successful Faculty Member: Essential Components," Workshop for Engineering Scholars, International Symposium on Electronic Systems Design – 2010, Bhubaneswar, India, December 20-22, 2010.
79. D. Misra, IEEE EDS Distinguished Lecture, "CMOS Nanoelectronics and Nanotechnology Evolution," Gandhi Institute of Technology and Management, IEEE EDS Bhubaneswar, India, December 18, 2010.
80. D. Misra, Distinguished Lecture, "TiN/High-k Gate Stacks for CMOS: Reliability Issues," SKP Engineering College, Tiruvannamalai, IEEE EDS Chennai, India, December 16, 2010.
81. D. Misra, "Faculty Success: Teaching Excellence," Temple City Institute of Technology and Engineering, Khurda, India, December 14, 2010
82. D. Misra, "How to be a Successful Faculty Member: Essential Components," BRCM College of Engineering and Technology, Bahal, Haryana, India, December 10, 2010.
83. D. Misra "Breakdown of TiN/High-k Gate Stacks in Nanoscale CMOS" IEEE Mini-Colloquium on Large Area Electronics, Friday, November 6, 2009, University of Waterloo, Waterloo, Canada
84. D. Misra, "Correlation of HCS and NBTI in Degradation of High-k Gate Dielectrics" International Symposium on Silicon Nitride, Silicon Dioxide, and Alternate Emerging Dielectrics 10, 215th Electrochemical Society Conference, San Francisco, CA , May 24- May 29, 2009.
85. D. Misra, *High-k Gate Dielectrics and Their Reliability*, Department of Electronics & Communication Engineering (ECE), Indian Institute of Technology, Guwahati, Assam at ECE Conference room on April 13, 2009 (Monday) at 3:00 PM. Host: Prof. S. Majhi, Dept. Chair and Prof. Roy P. Paily
86. D. Misra, *How to be a Successful Faculty Member*, Research Scholars' Forum Talk at Electrical Engineering Seminar Hall of IIT Bombay on April 2, 2009 (Thursday) at 4:00 PM. Host: Shamlan Reshamwala, President, Research Scholars Forum.
87. D. Misra, *General Trends in Nanoelectronics*, Sardar Patel College of Engineering, Bhavans Campus, Andheri (West), Mumbai on March 25, 2009 (Wednesday) at 4 PM. Host: Dr. S.Y. Mhaiskar, Principal.
88. D. Misra, *High-k Dielectrics on Alternate Substrates*, IEEE AP/ED BOMBAY CHAPTER DISTINGUISHED LECTURE at Nanoelectronics Conference Room, 3 rd Floor, EE Annex Building of IIT Bombay on March 5, 2009 (Thursday), 2009 at 4:30 PM. Host: Prof. Ramgopal Rao
89. D. Misra, *VLSI Design and CMOS Technology Evolution*, Sree Vidyanikethan Engineering College (SVEC), Sree Sainath Nagar, Tirupati, AP at Conference Hall on February 24, 2009 (Tuesday) at 12:00-2:00 PM. Host: Dr. P.C. Krishnamachary, Principal.
90. D. Misra, *CMOS Nanoelectronics and Nanotechnology Evolution*, Sree Vidyanikethan Engineering College (SVEC), Sree Sainath Nagar, Tirupati, AP at Conference Hall on February 24, 2009 (Tuesday) at 11:00 AM. Host: Dr. P.C. Krishnamachary, Principal.
91. D. Misra, *Current Trends in Nanoelectronics and Nanotechnology*, The Institution of Electronics and Telecommunications Engineers (IETE), Bhubaneswar Chapter along with IEEE – EDS Bhubaneswar Chapter Distinguished Lecture, BSNL Building 3rd Floor Seminar room on February 16, 2009 (Monday) at 7:00 PM. Host: Dr. Partha Sarkar, IEEE-EDS Chapter Chair and Er. Subrat Kumar Prusty, Secretary, IETE.
92. D. Misra, *Current Trends in Nanoelectronics and Nanotechnology*, The Ramniranjan Jhunjhunwala College, Mumbai, at Seminar Hall, Ground Floor of RJ College on January 30, 2009 (Friday), 2009 at 11:00 AM. Host: Dr. Usha Mukundan, Principal.
93. D. Misra, *Breakdown of Nanoscale CMOS Devices with TiN/High-k Gate Stacks*, IEEE AP/ED BOMBAY CHAPTER DISTINGUISHED LECTURE at Nanoelectronics Conference Room, 3 rd Floor, EE Annex Building of IIT Bombay on January 23 (Friday), 2009 at 4:30 PM. Host: Prof. Ramgopal Rao
94. D. Misra, High-k Gate Dielectric Reliability in Nanoscale CMOS, Electrical and Computer Engineering Department, University of Kentucky, Lexington, KY 40506, on November 18, 2008 (Tuesday), at 2:00 PM. Host: Prof. Zhi (David) Chen

95. D. Misra, *Reliability of Nanoscale CMOS Devices with High-k Gate Dielectrics*, Electrical and Computer Engineering Department, University of Louisville, Louisville, KY 40292, on November 17, 2008 (Monday), at 2:30 PM. Host: Prof. James H. Graham, Dept. Chair
96. D. Misra, "Reliability of High-k Dielectric Gate Stacks," IEEE Distinguished Lecturer, Department of Electrical and Computer Engineering, University of Waterloo, Waterloo, Canada, July 2, 2008.
97. D. Misra, "Reliability Concerns for sub-45nm CMOS Devices with High-K Gate Dielectrics," IEEE EDS Distinguished Lecture at National Technical University of Athens, Athens, Greece for EDS Greece Mini-Colloquium hosted by EDS Europe, Africa, and Middle East Regions/Chapters Subcommittee (SRC-EAM), June 2, 2008.
98. D. Misra, "Reliability of High-k Gate Dielectrics in sub-45nm CMOS Devices," IEEE EDS Distinguished Lecture at School of Engineering Sciences, Simon Fraser University, Vancouver, Canada, May 23, 2008.
99. D. Misra, "VLSI Design and CMOS Technology Evolution," IEEE EDS Distinguished Lecture at Nalanda Institute of Technology for EDS Bhubaneswar Chapter, Bhubaneswar, Orissa, India, March 14, 2008.
100. D. Misra, "Reliability Concerns for sub-45nm CMOS Devices," IEEE EDS Distinguished Lecture at WORKSHOP & IEEE EDS MINI-COLLOQUIA ON NANOMETER CMOS TECHNOLOGY (WIMNACT) 2008 ON NANO-ELECTRONICS, at Sikkim Manipal Institute of Technology, Majitar, Sikkim, India, March 6, 2008.
101. D. Misra, "Role of Interfacial Layer on Breakdown of TiN/High-k Gate Stacks," International Symposium on ULSI Process Integration 5, 212th Meeting of the Electrochemical Soc., Washington, DC, October 7-11, 2007.
102. D. Misra, Nanotechnology and Nanoelectronics Revolution, a Management Challenge, School of Management, NJIT, May 22, 2007.
103. D. Misra, Deuterium at the Si-Dielectric Interface in Nanoscale Devices, IEEE Distinguished Lecturer, February 21, 2007, IEEE NJ Section Electron Devices, Circuits and Systems Chapters, at NJIT
104. D. Misra, New Dielectrics for Sub-45nm CMOS Devices, IEEE Distinguished Lecture at Columbia University, February 14, 2007, IEEE New York Section.
105. D. Misra, Negative Bias Temperature Instability in TiN/Hf-based Gate Stacks, IEEE Distinguished Lecture at Indian Institute of Science, Bangalore, January 5, 2007. IEEE EDS Bangalore Chapter.
106. D. Misra, Nanoelectronics with Standard CMOS Devices and Beyond, IEEE EDS Mini-Colloquium on Microelectronics and VLSI, January 3, 2007, IEEE Calcutta Chapter at Bhubaneswar, India.
107. D. Misra, Introduction to VLSI Design, Institute of Technical Education and Research, Bhubaneswar, India, December 28, 2006. <http://iter.ac.in/>
108. D. Misra, Introduction to VLSI Design, Trident Academy of Creative Technology, at Bhubaneswar, India on December 20, 2006. <http://www.tat.ac.in/event.htm>
109. D. Misra, Nanoelectronics with CMOS Devices, IEEE Distinguished Lecturer, November 28, 2006, IEEE NJ Section LEOS Chapters, at NJIT.
110. D. Misra, "High-K Gate Dielectrics for sub-65nm CMOS Devices," IEEE Distinguished Lecture, University of Central Florida, **IEEE EDS Orlando Chapter**, February 24, 2006.
111. D. Misra and N. A. Chowdhury, , "Charge Trapping in High- Gate Dielectrics: A Recent Understanding", **Second International Symposium on Dielectrics for Nanosystems: Materials Science, Processing, Reliability, and Manufacturing**, 209th Electrochemical Society Meeting, Denver, Colorado, May, 2006.
112. D. Misra and R. Garg, Interface Characterization of High-K Dielectrics on Ge Substrates, **European – Material Research Society**, Nice, France, May-Jun 2006.
113. D. Misra, N.A. Chowdhury, and N. Rahim, Negative Bias Temperature Instability in TiN/Hf-Silicate Based Gate Stacks, **2006 Lester Eastman Conference on High Performance Devices**, Cornell University, August 2-4, 2006
114. D. Misra, "High-K Dielectrics for Nanoscale CMOS Devices,' Distinguished Lecture, **IEEE Electron Device Society Calcutta Chapter**, Jadavpur University, Kolkata, July 15, 2005
115. D. Misra, "Dielectrics for sub-65nm CMOS Devices,' Presented at the Graduate School, **Department of Physics, University of Delhi**, August 9, 2005.
116. T. Kundu and D. Misra, (Invited Paper) "Interface Passivation by Deuterium for Nanoscale CMOS Devices," **7th International Conference on Solid-State and Integrated Circuit Technology (ICSICT 2004)**, pp. Beijing, China, October 18-21, 2004.
117. D. Misra, N.A. Chowdhury, R. Garg, and P. Srinivasan, (Invited Paper) "Integration of High-K Dielectrics into Sub-65nm CMOS Technology: Requirements and Challenges," **IEEE TENCON 2004**, pp. TA11(1401), Chiang Mai, Thailand, 21-24 November 2004.
118. **D. Misra**, "Computer-Aided VLSI Design: A Current Perspective," National Institute of Science and Technology, Pallur Hills, India, June 14, 2003
119. **D. Misra**, "Systems Level Design to Physical Design: Current Trends in VLSI Design," Kalinga Institute of Industrial Technology, Bhubaneswar, India, June 4, 2003

120. **D. Misra**, Micro-Fabricated Microconcentrator for Volatile Organic Compound Sensors, University of Toledo Nanotechnology Research Center. October 2, 2001.
121. **D. Misra**, "Electrical Characterization of Thin Oxides Grown on Deuterium Implanted Silicon Substrate," **Fourth International Symposium on the Physics and Chemistry of SiO₂ and the Si-SiO₂ Interface**, 197th Meeting of the Electrochemical Society, Toronto, Ontario, Canada, May 14-18, 2000.
122. **D. Misra**, Process-Induced Damage to Deep-Submicrometer CMOS Transistors, **ASM International**, NJ Chapter Meeting, January, 26, 1999.
123. **D. Misra**, Electron Transit Time Estimation in Photodiodes for Ultra High Frame Rate (UHFR) Burst Image Sensors, November 4, 1998. POEM Annual Research Review of Photonics, Princeton. NJ.
124. **D. Misra**, "Recent Trends in VLSI Design," August 17, 1998, **Software Technology Park Seminar**, at Kalinga Institute of Industrial Technology, Bhubaneswar, India.
125. **D. Misra**, "Polarity Dependent Plasma Charging Damage in sub-um MOSFETs," July 10, 1998, Center for Advanced Research in Electronics Seminar at Indian Institute of Technology, New Delhi, India.
126. **D. Misra**, "Process Induced Damage (Plasma Damage) To CMOS Electronic Chips" November 4, 1997, **Sigma Xi Seminar** at NJIT.
127. **D. Misra**, A 3-Dimensional Magnetic Sensor and Its Applications, University of Aizu, Aizu-Wakamashu, Japan, March 20, 1995.
128. **D. Misra**, Processing of Strained SiGe Materials, **ASM International**, NJ Chapter, NJ, January 24, 1995.
129. **D. Misra**, Processing of Strained SiGe Materials, University of Aizu, Aizu-Wakamashu, Japan, March 20, 1995.
130. **D. Misra**, Effect of Dry Etching to Si_{1-x}Ge_x Devices, Naval Research Laboratory, Washington, DC, June 25, 1993.
131. **D. Misra**, "Physics of IC Design and Technology," Institute of Physics, Bhubaneswar, India, June 14, 1991.
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192. **D. Misra** and W.N. Carr, "Microengineered Sensors: A Review," Proceedings of the Electro/International (IEEE) Conference, New York, NY, April 16-18, 1991.
193. V. Patel, M. Patel, S. Ayyagari, **D. Misra**, W.F. Kosonocky, and B. Singh, M. Leahy, "Application of Thermal Imaging for Monitoring Wafer Temperature and End-Point Detection In Plasma Etching," SRC TECHCON '90, San Jose, CA, October 16-18, 1990.
194. **D. Misra**, Reactive Ion Etching (CF₄ + O₂ Plasma) Induced Deep Levels In MOS Devices," Presented at the 37th National Symposium of American Vacuum Society, Toronto, Canada, October 8-12, 1990.
195. V. Patel, M. Patel, S. Ayyagari, **D. Misra**, W.F. Kosonocky, and B. Singh, M. Leahy, "Wafer Monitoring by Infrared Camera During Plasma Etching: Analysis and Experimental Results," Presented at the New Jersey SEMATECH Center of Excellence for Plasma Etching - Annual Review, Princeton, NJ, August 7, 1990.
196. **D. Misra** and B. Pathak, "Design and Processing of Micromechanical Structures of Silicide Films," Proceedings of the Symposium of the Advanced Technology Center for Surface Engineered Materials (ATC/SEM), Hoboken, NJ, May 16, 1990.
197. **D. Misra**, "Modulus of Elasticity Measurement of Micromechanical Tungsten Silicide Cantilever Beams," (Poster Presentation), Consortium for Surface Processing, Rutgers University, June 8, 1989.
198. B. Pathak and **D. Misra**, "Modulus of Elasticity Measurement of Micromechanical Tungsten Silicide Cantilever Beams," Presented at the 36th National Symposium of American Vacuum Society, Boston, MA, October 23-29, 1989.
199. **D. Misra** and E.L. Heasell, "Annealing Behavior of Reactive Ion Etching Induced Deep Levels," 175th Meeting of the Electrochemical Society, 1989, Vol. 89-1, Abstract No. 168.
200. **D. Misra** and E.L. Heasell, "Side wall etching anisotropy due to CF₄ + O₂ RIE for the fabrication of V-groove emitter transistors," 172nd Meeting of the Electrochemical Society, 1987, Vol. 87-2, Abstract No. RNP - 1829.

Research Grants and Contracts

1. **NSF: (Co-PI)**, "REU Site: Optics and photonics: Technologies, Systems, and Devices," \$359,663.00, May 15, 2016 to April 30, 2019.
2. **NSF: (PI)**, KAUST-NSF Research Conference On Electronic Materials, Devices And Systems For A Sustainable Future 2015," \$25,000.00, January 15, 2015 - December 31, 2015.
3. **Heritage Institute of Technology, Kolkata, India: (PI)** Summer Research Institute for 99 Students, Summer 2009-2016, \$478,426, July 1, 2010 to June 30, 2017.
4. **Heritage Institute of Technology, Kolkata, India: (PI)** Summer Research Institute for 9 Students, Summer 2009, \$39,411, June 15, 2009 to June 15, 2010.
5. **Heritage Institute of Technology, Kolkata, India: (PI)** Summer Research Institute for 20 Students, Summer 2008, \$77,180, June 15, 2008 to June 15, 2009.
6. **NSF-4: (Co-PI)** A Research Experience for Undergraduates Site for Computer Networking and Security, Amount: \$300,000, Duration: March 1, 2006 to February 28, 2009.
7. **NASA/California Institute of Technology, Jet Propulsion Laboratory: (PI)** Back-Illuminated CMOS Imager Technology, NMO 715652, \$37,196.00, July 6, 2005 to September 30, 2007.
8. D. Misra, PI, **National Science Foundation** Award No. ECS 0140584, Passivation of Silicon Dangling Bonds by Deuterium Implantation, \$268,000, May 1, 2002 to April 30, 2006.
9. D. Misra, PI, **NSF REU Supplement** to ECS 0140584, \$12,000, May 1, 2002 to April 30, 2003.
10. D. Misra, PI, **NSF REU Supplement** to ECS 0140584, \$6,000, May 1, 2003 to April 30, 2004.
11. D. Misra, PI, Research in MEMS Using Bonded Wafers, **Sarnoff Corporation**, \$4,800.00, June 1, 2001 to December 2002.
12. D. Misra, Co-PI, New Jersey Center for Optoelectronics, **New Jersey Commission on Science and Technology**, \$75,000.00 (NJIT), March 1, 2001 to February 28, 2002 (With H. Grebel).
13. D. Misra, PI, A Micro-concentrator Interface for Real-time VOCs Sensors, **Center for Airborne Organics, An EPA Research Center at MIT**, with Prof. S. Mitra from Chem Eng. \$59,355.00, July 1, 2000 to December 31, 2001 (Amount allotted: Half of the total amount).
14. D. Misra, Co-PI, New Jersey Center for Optoelectronics, **New Jersey Commission on Science and Technology**, \$75,000.00 (NJIT share), March 1, 2000 to February 28, 2001 (with Prof. Grebel & Amount allotted: \$22,372).
15. D. Misra, Co-PI, Acquisition of Instrumentation for Deep Reactive Ion Etching of Bonded Ultra-Thin Silicon Wafers, **National Science Foundation**, \$467,380.00, July 15, 1998 to June 30, 1999 (With Prof.s Farmer and Mitra).
16. D. Misra, PI, Research Experience for Undergraduates (REU) Supplement Grant for Device And Materials Processing, **National Science Foundation**, \$10,000.00, January 1, 1999 to December 31, 2000.
17. D. Misra, PI, Acquisition of Specialized Instrumentation for Research & Development of Materials, Devices and

- Processes, **National Science Foundation**, \$55,000.00, July 15, 1998 to June 30, 1999.
18. D. Misra, Co-PI, New Jersey Center for Optoelectronics, **New Jersey Commission on Science and Technology**, \$85,000.00 (NJIT share), March 1, 1998 to February 28, 1999 (with Prof. Grebel & Amount allotted: \$22,000).
 19. D. Misra, PI, Fabrication of Students' VLSI design projects tiny-chips through MOSIS, **National Science Foundation**, an educational supplemental grant of \$1,785, October 1997 to April 30, 1998.
 20. D. Misra, PI, Investigation of Gate Oxides Grown on Light Deuterium Implanted Silicon Substrate, **Microelectronics Research Center**, NJIT, \$10,000, March 1, 1998 to June 30, 1999.
 21. D. Misra, PI, Air-gap Capacitance to Improve Interconnect Delay, **Microelectronics Research Center**, NJIT, \$10,000, March 1, 1998 to June 30, 1999.
 22. D. Misra, PI, "Two Part Nonvolatile Random Access Memory Using Conducting Polymer," **Infinite Computer Technologies (Air Force Office of Scientific Research , STTR Program)**, \$19,152.00, January 1, 1997 to December 31, 1997.
 23. D. Misra, PI, "Two Part Nonvolatile Random Access Memory Using Indium," **Rubicon Inc. (National Science Foundation, SBIR Program)**, \$19,885.00, June 1, 1997 to November 30, 1997.
 24. D. Misra, PI, "Silicon Photodetectors for Radiation Monitoring," **Radiation Monitoring Devices, Inc.**, \$19,000.00, Sept. 1, 1996 to Jan. 31, 1997.
 25. D. Misra, PI, "Research for Advanced CMOS Process," **Sarnoff Corporation**, \$24,000.00, December 1996 to May 1997.
 26. D. Misra, PI, "Design and Fabrication of Test Structures to Study the Reliability of Semiconductor Packaging," (Graduate Student Support & Training in Clean room) **Amkor Electronics Inc.**, \$74,000, July 1, 1996 to March 31, 1997.
 27. D. Misra, PI, Equipment Grant, "Upgrade to 6" Wafer Processing," **Amkor Electronics Inc.**, \$15,000 (cash award), January 1997.
 28. D. Misra, PI, "DLTS Measurement System," **Lucent Technologies (Allentown, PA)** Equipment donation, Equivalent cost \$10,000.00, May 1997.
 29. D. Misra, PI, Research Experience for Undergraduates, **National Science Foundation**, a supplemental grant of \$10,000, Jan. 1, 1995 to Dec. 31, 1995
 30. D. Misra, PI, Damage Elimination using an in-situ Contactless Sensor and Real Time Process Monitor During Plasma Etching in Microelectronic Manufacturing, **Center for Manufacturing Systems**, \$20,000, July 1, 1995 to June 30, 1996.
 31. D. Misra, PI, Study of Defects and Process Induced Damage in Si1-xGe Materials, **National Science Foundation**, \$141,000.00, September, 1, 1992 to June 30, 1996.
 32. D. Misra, PI, Study of Dry Etching Induced Damage in Silicon Dioxide, **SEMATECH Center of Excellence in NJ**, \$15,000, Aug. 1, 93 to Nov 30, 1993.
 33. D. Misra, Co-PI, Very-High-Frame-Rate Solid-State Sensor, **New Jersey Commission on Science and Technology**, \$75,000, W.F. Kosonocky PI, July 1, 1993 to June, 30, 1994 (Amount allotted: \$30,000).
 34. D. Misra, Co-PI, Design, Simulation and Prototype Fabrication of a Digital Compression Chip, **Digital Compression Technology, Inc.** \$130,000, Jan 4, 1993 to Dec 31, 1993. (Amount allotted: \$36,000).
 35. D. Misra, PI, Use of MOSIS for fabrication of VLSI chips, **National Science Foundation**, an educational supplemental grant of \$4,750, October, 1991 to August 1992.
 36. D. Misra, PI, Pre-Small Business Innovation Research Program, **Consortium For Surface Processing (ATC/SEM)**, \$5,000, October 1, 1991 - November 30, 1992.
 37. D. Misra, PI, VLSI Design and Signal Processing Laboratory, **Sun Microsystems Inc.** \$12,295, June 1, 1992, Equipment.
 38. D. Misra, PI, RIE Processed Micromechanical Systems (Cantilevers) Using Silicides, **Consortium For Surface Processing (ATC/SEM)**, \$27,600, June 1, 1989 - May 31, 1990.
 39. D. Misra, PI, Use of MOSIS for fabrication of VLSI chips for Small Projects, **National Science Foundation**, an educational supplemental grant of \$5,500, October, 1990 to August 1991.
 40. D. Misra, PI, Circuit Design, Analysis And Testing of A Novel CMOS Magnetic Field Sensor With A Temperature Compensation Scheme, **SIEMENS Corporate Research, Inc.** \$10,000, (June 1, 1989 - May 31, 1990).
 41. D. Misra, PI, VIMDE - A Vertically Integrated Multi-Chip-Module Design Environment, **AT&T Foundation**, \$22,000, May 31, 1990.
 42. D. Misra, PI, Electrical Breakdown Phenomena in Micromechanical Structures, **Consortium For Surface Processing (ATC/SEM)**, \$14,295, June 1, 1991 - May 31, 1992.
 43. D. Misra, PI, VLSI Design Softwares, Autologic etc, **Mentor Graphics Corporation**, \$370,000.00, January 1992.
 44. D. Misra, Co-PI, Wafer Monitoring During Plasma Etching by IR Camera, **SEMATECH Center of Excellence for**

Plasma Etching, Semiconductor Research Corporation, \$30,000, with Prof. W.F. Kosonocky CP, July 1, 1989 - June 30, 1990 (Amount allotted: \$10,000).

45. D. Misra, Co-PI, Trade-Off Study and Design of a Foveating Image Sensor For High Speed data Capture, **Rutgers University CAIP Center** \$15,000, with Prof. W.F. Kosonocky, CP, July 1, 1988 - June 30, 1989 (Amount allotted: \$8,000).

TEACHING

Courses Taught

FED 101 Fundamental of Engineering Design: Electrical Engineering Module
 EE 291 Electrical Engineering Laboratory
 EE 310 Cooperative Education and Internship
 EE 405 Electrical Engineering Principle
 EE 413 Introduction To Professional Engineering Practice
 EE 463 Microelectronics Devices
 EE 478 VLSI Semiconductor Circuits (Introduced New Course)
 ECE 648 Digital Microelectronics
 ECE 650 Electronic Circuits (Analog)
 ECE 658 VLSI Design – I (Introduced New Course)
 ECE 758 VLSI Design – II (Introduced New Course)
 ECE 789 Introduction to Design Using VHDL (Introduced initially as a Special Topic Course)

Short Courses:

1. D. Misra, Nanoelectronics Challenges for Internet of Things, **Global Initiative of Academic Networks (GIAN) Lecture at National Institute of Technology, Silchar**, India, January 5-9, 2017
2. **D. Misra**, Introduction to VLSI Design Using VHDL, A Two Days Intensive Course at **Computer Science Department, Texas A&M University**, College Station, Texas, June 14-15, 1999.
3. **D. Misra**, "Introduction to VLSI Design and VHDL," at Sarnoff Corporation, Princeton, New Jersey, May 18, 1998 to July 7, 1998 (8 weeks), **Sponsored by Sarnoff Corporation**.
4. **D. Misra**, Two Days Intensive Course on "Principles and Recent Advances in VLSI Design - Use of VHDL as VLSI Design Tool," at National Institute of Science and Technology, Palur Hills, Berhampur, India, July 20th and 21st, 1998, **Sponsored by Council for Industrial and Scientific Research (CSIR), India**.

New Courses Developed:

ECE 475-001 VLSI Semiconductor Circuits.
ECE 658-101 VLSI Design - I.
ECE 758 VLSI Design – II.

Other Teaching Related Activities

- Excellence in Teaching Award, New Jersey Institute of Technology, 2005
- Nominated by ECE Department for Excellence in Teaching Award for Graduate Instruction.
- Course Supervisor for the courses ECE 475 (since Fall 1990) and ECE 658 (since Fall 1988).
- Receiving \$1,500 to \$5,000 per year from **National Science Foundation/DARPA** to fabricate students' designs as part of their course projects.
- Received Grants as PI and Co-PI for instructional laboratory development.
- Contributing to the Computer Engineering program through CAD services.
- First time introduced VHDL course at NJIT.

GRADUATE STUDENT ADVISING

Post-Doctoral Fellows

- R.K. Jarwal, January 1999 to Present, **Research Work:** Simulation of Ultra High Frame Rate Imager) and CMOS Device Physics and reliability, Supported by New Jersey Center for Optoelectronics. Currently as Research Engineer at NJIT.
- P.K. Swain, March 1995 to May 1997, **Research Work:** Processing of SiGe Devices and materials, as per NSF proposal, **Development Work:** Developed the CMOS process in NJIT clean room. Currently as CTO and VP Technology at Fusion UV Systems, Inc, Gaithersburg, MD

Doctoral Students (Current)

Peter Paliwoda, Tri-Gate Transistors design

Rui Yuan, Meta-Analytic Parcellation Based on Text, and its application to the human thalamus

Meenakshisundar Gurunathan, RF Devices and Circuits: Active tunable inductors

Balamurali Bhat, RF Devices and Circuits: Low noise oscillators

Nathaniel McCaffrey, *Dissertation Title:* Design of Drift Field Voxel (DFV) for Efficient Detection.

Expected Graduation Date: December 2012

Doctoral Students (Graduated)

Yiming Ding, Electrical Characterization of High-K Gate Dielectrics for Advanced CMOS Gate Stacks

Graduation Date: August 2016, Currently at SMIC, Shanghai, China

M.N. Bhuyian, Reliability Study of Zr and Al Incorporated Hf-based High-k Dielectric Deposited by Advanced Processing,

Graduation Date: January 2015, Currently post-doc at NJIT.

P. Kharangarh, Study of Deep Level Defects of n+-CdS/p-CdTe Solar Cells, jointly supervised by Dr. K. Chin of Physics,

Graduation Date: May 2013.

Vinay Budhbraja, *Dissertation Title:* Defects in Multicrystalline Silicon: Influence on Solar Cell Performance

Graduation Date: December 2011, Currently in Finland

Santosh Sahoo, *Dissertation Title:* High Temperature-Stress Induced Leakage Current (HT-SILC) Analysis of

High-K Gate stacks. *Graduation Date:* December 2012

Zhi Li, *Dissertation Title:* Design and Fabrication of a Fluorescence Detector

Graduation Date: May 2012 Currently working at Brookhaven National Laboratory (BNL), Upton, NY 11973

Nilufa Rahim, TiN/HfO₂/SiO₂/Si Gate Stacks Reliability: Contribution of HfO₂ and

Interfacial SiO₂ Layer, *Graduation Date:* January 2011, Currently with IBM Burlington.

P. Srinivasan, Reliability Study of Nanoscale MOS Transistors with High-K Gate Dielectrics”

PhD Thesis, *Graduation Date:* May 2007. Currently at Globalfoundries, NY

N.A. Chawdhury, “Low Temperature Trapping Characteristics of HfO₂ Gate Dielectrics”

PhD Thesis, *Graduation Date:* December 2006. Currently at Spansion Inc, CA

R. Garg, “Ge MOS Devices with Thermally Evaporated HfO₂ as Gate Dielectrics”

PhD Thesis, *Graduation Date:* January 2006. Currently at Infineon Technologies, CA

T. Kundu, “Isotope Effect at Si/SiO₂ Interfaces,”

PhD Thesis, *Graduation Date:* August 2005. Currently at Micron Technologies, VA

M. Kim, “Microconcentrator Interface for Chemical Sensors,” Supported by MRC, Jointly supervised by Dr. S. Mitra of

Chem. Eng. Currently at US Dept of Commerce, Washington, DC

PhD Thesis, *Graduation Date:* Summer 2002.

Wei Zhong, “Process Induced Damage and Defects

to Materials and Devices,” Supported by NSF and Anadigics.

PhD Thesis, May 2001. **Winner of ECE Department’s 2001 Hashimoto Award.**

Current Employment: Anadigics, Warren, NJ

R.K. Kabra, “Design and Characterization of Ultra High Frame Rate Burst Image Sensors,” Supported by PSI Inc and Sarnoff Corp.

PhD Thesis, January 1998

Current Employment: Sarnoff Corporation, Princeton, NJ.

K.R. Linga, Design, “Fabrication and Characterization of High Performance InGaAs/InP Focal Plane Arrays in the 1-2.6μm Wavelength Region,” Supported by PSI Inc and Epitaxx.

PhD Thesis, May 1997, Current Employment: President, InPhot Inc., NJ

Masters Graduates

Nayana Vishwanath, MS Project, FPGA Implementation of baseband equivalent discrete time system transmitter model, December 2014.

Amrita Banerjee, MS Thesis Title: Fabrication And Characterization Of High Performance Si-SiO₂ Back Illuminated CMOS Photodiode Array, August 2006.

Jagtar S. Dhillon, MS Project:

Ravishankar B. Bannigidadmath, MSEE, Project Title: Performance Evaluation of Low Power SRAM in Deep Submicron Technology, January 2005.

Don Guelich, MSEE, Project Title: Custom Dither ASIC for "Full Color" on 18-bit LCD, August 2005.

Purushothaman Srinivas, "VLSI Architecture for Deadlock Avoidance in Wormhole Networks," M.S. Thesis: January 2004.

Soumya Das Sharma, "Chip Design for Multicast Oriented Routing Algorithm," M.S. Project: January 2004.

Bhawar Patel, "MOSFET Degradation with Reverse Biased Source and Drain During High-Field Injection," M.S. Thesis: Aug 2003.

Harsha R. Sipuram, "Low power transceiver design for mobile wireless chemical and biological sensors, M.S. Thesis: May 2003

Y. Ramakrishna Vadapalli, "An Interface chip for SWA based chemical sensor in ad-hoc networks," M.S. Thesis: January 2003

Vishnu Mandava, "VLSI Design Of Stability Routing Protocol For Sensors In Manets," M.S. Thesis, January 2003.

Reenu Garg, "Chip Design for Multicast Oriented Routing Algorithm," M.S. Project: January 2003.

Damanjeet Chandok, "Video Processing in a Machine Vision System," M.S. Project: January 2003

K. Gururaj, "VLSI Architecture for Deadlock Avoidance in Wormhole Networks," M.S. Thesis, August 2002.

S. Polturi, "Hyperbolic Position Location Estimator with TDOA from Four Stations," M.S. Thesis, Fall 2001.

R. Bucher, "A Synthesizable Low Power VHDL Model of the Exact Solution of Three Dimensional Hyperbolic Positioning System," M.S. Project, January 2000.

S. Kishore, "Investigation of Gate Oxides Grown on Light Deuterium Implanted Silicon Substrate," M.S. Thesis, August 1999.

P. Mohare, "Generic Emulation of Microprocessors," M.S. Thesis, May 1999.

S. Madapur, "Design, Simulation and Fabrication of a Two-Part Non Volatile Random Access Memory Circuit," M.S. Thesis, January 1998.

S. Ganesh, "Design, Simulation and Fabrication of a MEMS In-situ, Contactless Sensor to Detect Plasma Induced Damage During Reactive Ion Etching," M.S. Thesis, January 1997.

Y. Qiu, "The Study of SiGe-Channel Heterostructure MOS Device," M.S. Thesis, May 1996.

P. Patel, "Design of Neuron Cell Using FPGA," M.S. Project, May 1996.

J. Shah, Graduated, "Automation of Reactive Ion Etching Process using a MC 68000 Microprocessor," M.S. Thesis, August 1993.

B. Wang, "Three Dimensional Magnetic Sensors and Array in BiCMOS Technology" M.S. Thesis, January 1993.

L. Simhadri, "A Verilog Model for VLSI Implementation of Mathematical Morphology Operations," M.S. Project, May 1992.

A. Shah, "A Novel Micromachined Beam-Diaphragm Structure for High Performance Pressure Transducers," M.S. Thesis, August 1991.

V. Satyanarayana, "A 4-Bit BiCMOS Full Adder for ALU," M.S. Project, May 1991.

O. Ezebuioch, "Offset Cancellation in a MAGFET," M.S. Project, May 1991.

T. Jaswal, "A CMOS Logic Circuit to Reduce Substrate Current/Hot Carrier Effect," M.S. Thesis, May 1991.

S. Patel, "An n-Channel MOSFET with Schottky Source and Drain," M.S. Project, December 1990.

M. Zhang, "3-D Magnetic Field Sensor Design Based on Standard IC Technology," M.S. Thesis, December 1990.

D.K. Sampath, "A Novel CMOS Magnetic Field Sensor with Temperature Compensation Scheme," M.S. Thesis, December 1990.

V.S. Simhadri, "A Novel Schottky Barrier MOSFET for VLSI Applications," M.S. Thesis, August 1990.

B. Pathak, "Investigation of Micromechanical Properties of Tungsten Silicide Thin Films," M.S. Thesis, August 1990.

M.D. Bunyan, "Damage Effects in Si-SiO₂ Structures Due to Reactive Ion Etching," M.S. Thesis, May 1990.

Y. Chakravarthy, "A 512x512 Random Addressable Variable Resolution Image Sensor," M.S. Thesis, March 1990.

PROFESSIONAL ACTIVITIES:

Editorial Activities

1. Editorial Board, *Materials* (Journal) 2014-present
2. Special Issue Editor, *Materials* (Journal) on High-K Gate Dielectrics (2014)
3. Associate Editor, *Advances in Electronics* January 2014 – 2016
4. Editorial Board, *ECS Interface Magazine*, May 2008 - Present
5. Editorial Board, *ECS Transactions*, May 2010 - May 2015

The Electrochemical Society (ECS)

- Symposium Chair and Lead Editor, Dielectrics for Nanosystems, May 2004 – present, ECS Meetings: Manuscript review and Session Chairing activities.
- Committee Member, Honors and Awards Committee of The Electrochemical Society. Appointed, May 15, 2012 – May 15, 2016).
- Symposium Organizing Committee Member and Editor, Semiconductors, Dielectrics, and Metals for Nanoelectronics, January 2002 – Present, ECS Meetings, Manuscript review and Session Chairing activities.
- Symposium Organizing Committee Member and Editor, Graphene and Post-CMOS Materials and Devices – Present, ECS Meetings, Manuscript review and Session Chairing activities.
- Fellow of Electrochemical Society
- Serving as the Vice-Chair of the Dielectric Science and Technology Division of the Society 2006-2008.
- Served as the Secretary of the Dielectric Science and Technology Division of the Society 2004-2006.
- Serving in the **Executive Committee** of the **Dielectric Science and Technology Division** of the Society.
- Awards Committee Member, Solid State Science & Technology Award, Electrochemical Society, May 2000.
- Chair, Awards Committee, Thomas D. Callinan Award, Electrochemical Society, May 2000-2004.
- Chair, Membership Committee of Dielectric and Science Division of Electrochemical Society in May 1998 to May 2001.
- Providing Travel Grants and Awarded Memberships to Students all over the world to present a paper in all the ECS meetings since October 1998.

International Symposia at ECS

- Co-organizer & Session Chair, International Symposium on High Dielectric Constant Materials: Material Science, Processing, Manufacturing and Reliability Issues (S. Kar, R. Singh, **D. Misra**, H. Iwai, M. Houssa, J. Morais, D. Landheer), 204th Meeting – Orlando, FL, October 12-16, 2003 in collaboration with the Electronic Division of American Ceramic Society.
- Co-organizer & Session Chair, H1 – Interfaces in Electronic Materials (L.P. Cook, **D. Misra**, S.M. Mukhopadhyay, O. Leonte, K. Sundaram, W. Wong-Ng), 204th Meeting – Orlando, FL, October 12-16, 2003 in collaboration with the Electronic Division of American Ceramic Society.
- Co-organizer & Session Chair, H1 - First International Symposium on High Dielectric Constant Materials: Material Science, Processing, Manufacturing and Reliability Issues, 202nd Meeting - Salt Lake City, UT, October 20-24, 2002
- Co-organizer & Session Chair, H2 - Emerging Technologies in Nanoelectronics (D. Misra, K.B. Sundaram and S. Seal), 202nd Meeting - Salt Lake City, UT, October 20-24, 2002
- Co-organizer & Session Chair, F1 - Science and Technology of Dielectrics in Emerging Fields (D. Misra, K. Worhoff, P. Mascher), 203rd Meeting - Paris, France, April 27-May 2, 2003.
- Co-organizer & Session Chair, G1 - Seventh International Symposium on Silicon Nitride and Silicon Dioxide Thin Insulating Films (R.E. Sah, K.B. Sundaram, M.J. Deen, D. Landheer, W.D. Brown, D. Misra), 203rd Meeting - Paris, France, April 27-May 2, 2003.
- Co-organizer, International Symposium on *Silicon Nitride and Silicon Dioxide Thin Insulating Films – VI* at the 199th Meeting of Electrochemical Society at Washington, DC March 25-29, 2001.
- D. Misra: Session Chair, International Symposium on *Silicon Nitride and Silicon Dioxide Thin Insulating Films – VI* at the 199th Meeting of Electrochemical Society at Washington, DC March 25-29, 2001.
- Co-organizer, International Symposium on Microfabricated Systems And MEMS-V at the 198th Meeting of Electrochemical Society at Phoenix, Arizona October 22-27, 2000.

- D. Misra: Session Chair, International Symposium on Microfabricated Systems and MEMS V, 198th Meeting of Electrochemical Society, Phoenix, Arizona, October 22-27, 2000.
- Co-organizer, International Symposium on Plasma Etching Processes For Sub-Quarter Micron Devices at the 196th Meeting of Electrochemical Society and 1999 Joint International Meeting at Honolulu, Hawaii, October 17-22, 1999. Chaired a Session in the Symposium.
- Co-organizer, International Symposium Interconnects And Contact Metallization For ULSI at the 196th Meeting of Electrochemical Society and 1999 Joint International Meeting at Honolulu, Hawaii, October 17-22, 1999. Chaired a Session in the Symposium.
- Co-organizer, Student Poster Session at the 196th Meeting of Electrochemical Society and 1999 Joint International Meeting at Honolulu, Hawaii, October 17-22, 1999. Chaired the Session in the Symposium.
- 23 • Co-organizer, International Symposium on Fifth International Symposium On Silicon Nitride And Silicon Dioxide Thin Insulating Films, Processes and Reliability at the 195th Meeting of Electrochemical Society at Seattle, WA, May 1999. Chaired a Session in the Symposium.
- Organizer, Student Poster Session at the 195th Meeting of Electrochemical Society at Seattle, WA, May 1999. Chaired a Session in the Symposium.
- Co-organizer, International Symposium on Interconnect and Contact Metallization: Materials, Processes and Reliability at the 194th Meeting of Electrochemical Society at Boston, MA, November 1998. Chaired a Session in the Symposium.
- Co-organizer, Fifth International Symposium on Quantum Confinement: Nanostructures at the 194th Meeting of Electrochemical Society at Boston, MA, November 1998. Chaired a Session in the Symposium.
- Co-organizer, International Symposium on Microstructures and Microfabricated Systems IV at the 194th Meeting of Electrochemical Society at Boston, MA, November 1998. Chaired a Session in the Symposium.
- Organizer, Student Poster Session at the 194th Meeting of Electrochemical Society at Boston, MA, November 1998. Chaired a Session in the Symposium.
- Co-organizer, International Symposium on Plasma Processing at the 193rd Meeting of Electrochem Soc at San Diego, CA, May 1998. Chaired a Session in the Symposium.
- Organizer, Student Poster Session at the 193rd Meeting of Electrochemical Society at San Diego, CA, May 1998. Chaired a Session in the Symposium.

Institute of Electrical and Electronics Engineers (IEEE)

- IEEE Electron Device Society Board of Governors, January 1, 2015 - Present.
- Chairperson, North Jersey Section of IEEE: EDS Chapter, North Jersey Section, New Jersey. Elected, (January 1, 2010 - Present)
- Steering Committee Member, IEEE International Conference on Information Technology, May 1, 1999 - Present).
- Steering Committee Member, IEEE International Symposium on Electronic System Design (ISED) May 1, 2011 – Present).
- Chairperson, North Jersey Section of IEEE: EDS Chapter, North Jersey Section, New Jersey. Elected, (January 1, 2010 - Present).
- Associate Editor, IEEE Circuits and Device Magazine till 2006.
- Special Section Editor (Column Editor: **Device Unlimited**), IEEE C&Devices Magazine till 2006
- Senior Member of the IEEE
- Chair, North Jersey Section of IEEE 2003 and 2004.
- ADCOM Member IEEE Electron Device Society, 2004.
- Editorial Board Meeting, IEEE Circuits and Devices Magazine, Orlando, FL, Nov. 18, 2000.
- Editorial Board Meeting, IEEE C and D Magazine, San Francisco, CA, June 23, 2001.
- Treasurer, IEEE North Jersey Section, for 2001 and 2002.
- 2000 (elected) Member at Large of the North Jersey Section of the IEEE.
- Presently serving as the Associate Chair of Electron Device Society and Circuit and Systems division of the North Jersey Section of IEEE.
- Represented North Jersey Section of IEEE since 1997 the National Meeting of the Electron Device Society at IEDM.
- Organizing seminars at NJIT campus for IEEE.
- A constant reviewer of articles for International Journals such as IEEE Transaction on Electron Devices, IEEE Electron Device Letters.
- Session Chair, VLSI Technology Session, VLSI Design 2001, 14th International Conference on VLSI Design, January 5, 2001.

- D. Misra: Program Committee Member, Int. Conf. on VLSI Design, 01, 02, 03, 04 & 05

International Conference on Information Technology

- D. Misra: Program Committee Member, International Conference on Information Technology, 2001, 2002, 2003, 2004.
- D. Misra: Session Chair, Session for Keynote Papers, International Conference on Information Technology, Bhubaneswar, India, Dec. 21-23, 2000.
- Served as the **Program Chair** of International Conference on Information Technology, CIT'2000, in Bhubaneswar, India, December 21-23, 2000.
- 24 • Served as the **Tutorial Chair** of International Conference on Information Technology, CIT'99, in Bhubaneswar, India, December 20-22, 1999.
- Served in the **Technical Program Committee** of International Conference on Information Technology, CIT'98, in Bhubaneswar, India, December 21-23, 1998.
- Submitted a proposal to NSF to support CIT'2000.

Reviewing Activities

- Regular Reviewer of articles for International Journals:
 - IEEE Transaction on Electron Devices
 - IEEE Electron Device Letters
 - IEEE/ECS Electrochemical and Solid-State Letters
 - IEEE Transaction on Circuit and Systems
 - Applied Physics Letter (AIP)
 - Journal of Applied Physics (AIP)
 - Journal of Vacuum Science and Technology (AVS)
 - Journal of the Electrochemical Society
 - Journal of Physics D: Applied Physics
 - Journal of Micromechanics and Microengineering
 - Material Science in Semiconductor Processing
 - Nanotechnology
 - Semiconductor Science & Technology
 - Grant Proposals for National Science Foundation.
- Awarded Membership of The Institute of Physics, London, 2000 for Reviewing Activities.
- Served as a Panel Member in Enabling Technology Division (ECS) of NSF in June 1998 to review 24 proposals.
- Served as a Panel Member in Enabling Technology Division (ECS) of NSF in May 2001 to review 8 individual MRI proposals and 34 proposals in the panel.
- Served as a Panel Member in Enabling Technology Division (ECS) of NSF in October 2003 to review 21 individual career proposals in the panel.

University Service

- Provided an outstanding service with leadership as the Acting Director of Microelectronics Research Center in 1996-97 Academic Year.
- Provided an outstanding service as a Mentor for University Research Experience program for Undergraduates in Equal Opportunity Program, New Jersey State Minority Academic Career Program, McNair Fellow Program (99-00) for last several years (since 1995-96).

University Committees

- Served in the University Research Committee
- Serving in the Graduate Studies Committee for Best Thesis
- Served in the Academic Computing Committee
- Served as the Library Committee

Departmental Committees

- Director, Graduate Program: MS Electrical Engineering.
- Area Coordinator: Solid-State, VLSI and Electro-Optics Systems
- Served in the Chairperson Search Committee (elected)
- Currently serving in (i) Committee of Committees (elected), (ii) Doctoral Committee, (iii) Financial Aid Committee.
- Served as the Computer Engineering Faculty Search Committee for two academic years in 1997-98 and 1998-99.
- Served as the Chair of the departmental A&V committee.
- Served as the Assistant Director of the Electronic Imaging Center at NJIT and established the VLSI/CAD facility for the Center.

PUBLIC SERVICE

- Secretary Treasurer, Orissa Society of Americas, New York Chapter, 2002-2004.
- Participated as a Panel Member at the One day Workshop on Rebuilding Orissa (India) after Killer Cyclone on Saturday, February 5, 2000, University of Maryland, College Park, MD.
- An active volunteer member at the “Sustainable Economic and Educational Developmental Society (SEEDS) [<http://www.seedsnet.org>]. SEEDS has been active to promote educational and economic progress and development for the common folks particularly in Orissa, but in the developing world in general. SEEDS in principle, also would take stand against social evils and injustices whenever possible. SEEDS best hope that these, in turn, would indirectly bring about and foster the other important ingredient – political consciousness and empowerment-- among the people.
- Serving as a fund raiser and volunteer for the Orissa Cyclone Relief Program
- Served as Vice President of Orissa Society of Americas’ New York Chapter 1998-2000.
- Served as an advisor to Association of Indian Students at NJIT.
- Served as an organizer for the 25th National Convention of Orissa Society of Americas in 1994.
- Member SPIE, Sigma Xi.